

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Inventors: Dragan PETROVIC, et al.
Application No.: New PCT National Stage Application
Filed: February 11, 2005
For: METHOD OF PROCESS MANAGEMENT FOR MULTIPLE HARQ
PROCESSES

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner of Patents
Washington, DC 20231

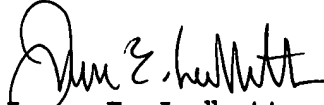
Sir:

Pursuant to Rules 56 and 99, Applicants hereby call the attention of the Patent Office to the references listed on the attached Form PTO 1449. All of these references were cited in a PCT International Search Report (copy attached). The S. Kallel article is discussed at page 1, paragraph 3, of the present specification.

Applicants present this art so that the Patent Office may, in the first instance, determine any relevancy thereof to the presently claimed invention, see Beckman Instruments, Inc. v. Chemtronics, Inc., 439 F.2d 1369, 1380, 165 USPQ 355, 364 (5th Cir. 1970). Also see Patent Office Rules 104 and 106.

Applicants respectfully request that this art be expressly considered during the prosecution of this application and made of record herein and appear among the "References Cited" on any patent to issue herefrom.

Respectfully submitted,



James E. Ledbetter

Registration No. 28,732

Date: February 11, 2005

JEL/spp

ATTORNEY DOCKET NO. L7725.05102

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ATTY. DOCKET NO.

SERIAL NO.

L7725.05102

New PCT Nat'l Stage Application

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Dragan PETROVIC, et al.

FILING_DATE

February 11, 2005

GROUP

Unassigned

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

PCT International Search Report dated September 23, 2003.

S. KALLEL, et al.: "Throughput Performance fo Memory ARQ Schemes," IEEE TRANSACTIONS ON VEHICULAR TECHNOLOGY, IEEE INC., NEW YORK, US, vol. 48, no. 3, May 1999, pp. 891-899, XP000906444, ISSN: 0018-9545.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.